

Search Notes	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10824434	YOON ET AL.
	Examiner	Art Unit
	Tan, Alvin H	2173

SEARCHED			
Class	Subclass	Date	Examiner
715	744, 747	5/3/07 (Updated 5/20/08)	/AT/ (/AT/)

SEARCH NOTES			
Search Notes	Date	Examiner	
715/744-747 (text search only - see search history printout)	5/3/07 (Updated 5/20/08)	/AT/ (/AT/)	
EAST (US-PGPUB, USPAT, USOCR, EPO, JPO, IBM_TDB) - See Search History Printout	5/3/07 (Updated 5/20/08)	/AT/ (/AT/)	
NPL - ACM Portal	5/4/07	AT	

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner